

<b>Notice of References Cited</b>	Application/Control No. 10/788,869		Applicant(s)/Patent Under Reexamination GOON, BEN NEE	
	Examiner Janice A. Mooneyham		Art Unit 3629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,418,551	07-2002	McKay et al.	716/5
*	B	US-2005/0188336	08-2005	Mortensen et al.	716/005
*	C	US-6,115,546	09-2000	Chevallier et al.	716/5
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	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Dallas Semiconductor Quality Manual published 5/30/02 retrieved from the Internet
	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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